

## 1. Description

This power MOSFET is produced with advanced technology of KIA. This technology enable the power MOSFET to have better characteristics, including fast switching time, low on resistance, low gate charge and especially excellent avalanche characteristics.

## 2. Features

- $R_{DS(on)Typ}=4.6m\Omega @ V_{GS}=10V$
- Low gate charge ( typical 148nC)
- High ruggedness
- 100% avalanche tested
- Improved dv/dt capability

## 3. Application

- Synchronous Rectification
- Li Battery Protect Board
- Inverter

## 4. Pin configuration



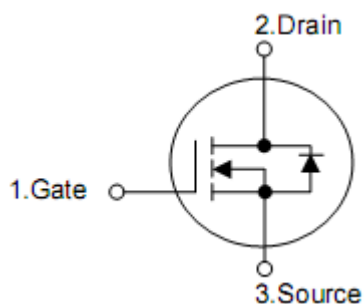
TO-263



TO-220



TO-3P



Pin	Function
1	Gate
2	Drain
3	Source

## 5. Ordering Information

Part Number	Package	Brand
KNP2906B	TO-220	KIA
KNB2906B	TO-263	KIA
KNH2906B	TO-3P	KIA

## 6. Absolute maximum ratings

$T_C=25^{\circ}\text{C}$  unless otherwise specified

Parameter	Symbol	Ratings		Units
		TO-220,TO-263	TO-3P	
Drain-Source Voltage	$V_{DSS}$	60		V
Drain Current	$T_C=25^{\circ}\text{C}$	130*		A
	$T_C=100^{\circ}\text{C}$	91*		A
Drain Current Pulsed <sup>1)</sup>	$I_{DM}$	580		A
Gate-Source Voltage	$V_{GSS}$	$\pm 20$		V
Single Pulsed Avalanche Energy <sup>2)</sup>	EAS	506		mJ
Repetitive Avalanche Energy <sup>1)</sup>	$E_{AR}$	50		mJ
Peak Diode Recovery $dv/dt$ <sup>3)</sup>	$dv/dt$	5		V/ns
Power Dissipation	$T_C=25^{\circ}\text{C}$	195.3	312.5	W
	Derating factor above $25^{\circ}\text{C}$	$P_D$	1.56	2.5
Operating and Storage Temperature Range	$T_J, T_{STG}$	-55 to +150		$^{\circ}\text{C}$
Maximum lead temperature for soldering purposes, 1/8 from case for 5 seconds	$T_L$	300		$^{\circ}\text{C}$

\* Drain current is limited by junction temperature.

## 7. Thermal characteristics

Parameter	Symbol	Ratings		Unit
		TO-220,TO-263	TO-3P	
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	0.64	0.4	$^{\circ}\text{C}/\text{W}$
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	45	35	$^{\circ}\text{C}/\text{W}$

## 8. Electrical characteristics

(T<sub>J</sub>=25°C, unless otherwise notes)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	60	-	-	V
Breakdown Voltage Temperature Coefficient	$\frac{\Delta BV_{DSS}}{\Delta T_J}$	I <sub>D</sub> =250μA, Referenced to 25°C	-	0.05	-	V/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =68V, V <sub>GS</sub> =0V	-	-	1	μA
		V <sub>DS</sub> =54V, T <sub>J</sub> =125°C	-	-	50	μA
Gate-Body Leakage Current, Forward	I <sub>GSSF</sub>	V <sub>GS</sub> =20V, V <sub>DS</sub> =0V	-	-	100	nA
Gate-Body Leakage Current, Reverse	I <sub>GSSR</sub>	V <sub>GS</sub> =-20V, V <sub>DS</sub> =0V	-	-	-100	nA
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	2	-	4	V
Static Drain-Source On-Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =30A, T <sub>J</sub> =25°C	-	4.6	5.4	mΩ
		V <sub>GS</sub> =10V, I <sub>D</sub> =30A, T <sub>J</sub> =125°C	-	7.5	-	mΩ
Forward Transconductance	g <sub>FS</sub>	V <sub>DS</sub> =5V, I <sub>D</sub> =30A	--	64	-	S
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> =34V, V <sub>GS</sub> =0V, f=1.0MHz	-	6564	-	pF
Output Capacitance	C <sub>oss</sub>		-	553	-	pF
Reverse Transfer Capacitance	C <sub>rss</sub>		-	396	-	pF
Turn-On Delay Time	t <sub>d(on)</sub>		-	35	-	ns
Turn-On Rise Time	t <sub>r</sub>	V <sub>DS</sub> =34V, I <sub>D</sub> =30A, R <sub>G</sub> =4.7Ω, V <sub>GS</sub> =10V <sup>4),5)</sup>	-	78	-	ns
Turn-Off Delay Time	t <sub>d(off)</sub>		-	135	-	ns
Turn-Off Fall Time	t <sub>f</sub>		-	60	-	ns
Total Gate Charge	Q <sub>g</sub>		V <sub>DS</sub> =54V, I <sub>D</sub> =30A, V <sub>GS</sub> =10V, I <sub>G</sub> =5mA <sup>4),5)</sup>	-	148	-
Gate-Source Charge	Q <sub>gs</sub>	-		32	-	nC
Gate-Drain Charge	Q <sub>gd</sub>	-		53	-	nC
Gate resistance	R <sub>g</sub>	V <sub>DS</sub> =0V, Scan F mode	-	3.2	-	Ω
Maximum Continuous Drain-Source Diode Forward Current	I <sub>S</sub>	Integral reverse p-n Junction diode in the MOSFET	-	-	145	A
Maximum Pulsed Drain-Source Diode Forward Current	I <sub>SM</sub>		-	-	580	A
Drain-Source Diode Forward Voltage	V <sub>SD</sub>	V <sub>GS</sub> =0V, I <sub>S</sub> =45A	-	-	1.4	V
Reverse Recovery Time	t <sub>rr</sub>	V <sub>GS</sub> =0V, I <sub>S</sub> =30A, di <sub>F</sub> /dt=100A/us	-	42	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>		-	64	-	nC

Note:

1. Repetitive rating: pulse width limited by junction temperature.
2. L=0.5mH, I<sub>AS</sub>=45A, V<sub>DD</sub>=50V, R<sub>G</sub>=25Ω, Starting T<sub>J</sub>=25°C
3. I<sub>SD</sub>≤30A, di/dt=100A/us, V<sub>DD</sub>≤BV<sub>DSS</sub>, Starting T<sub>J</sub>=25°C
4. Pulse Test: Pulse Width≤300us, duty cycle≤2%.
5. Essentially independent of operating temperature.

## 9. Typical Characteristics

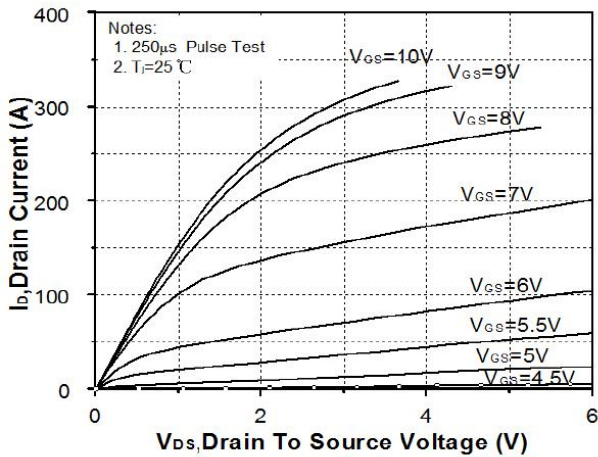


Fig. 1. On-state characteristics

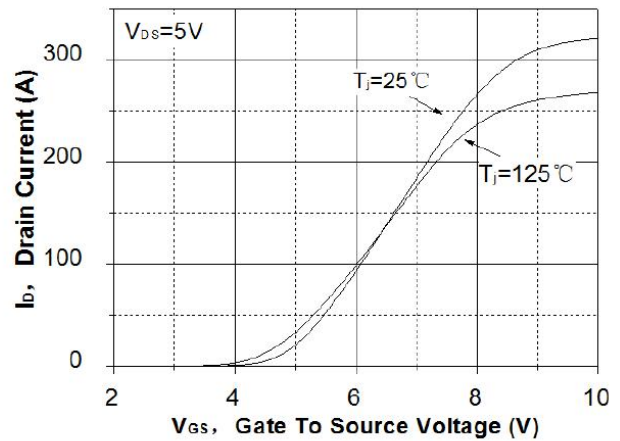


Fig. 2. Transfer Characteristics

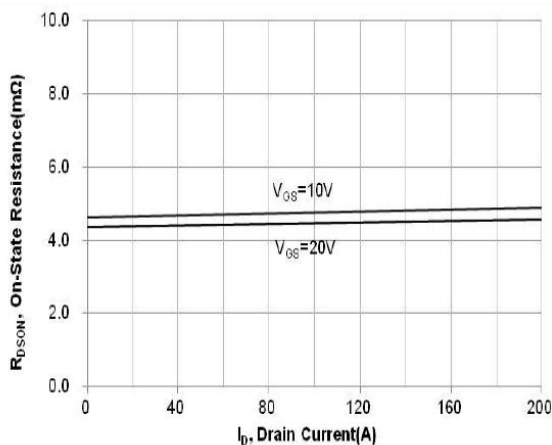


Fig. 3. On-resistance variation vs. drain current and gate voltage

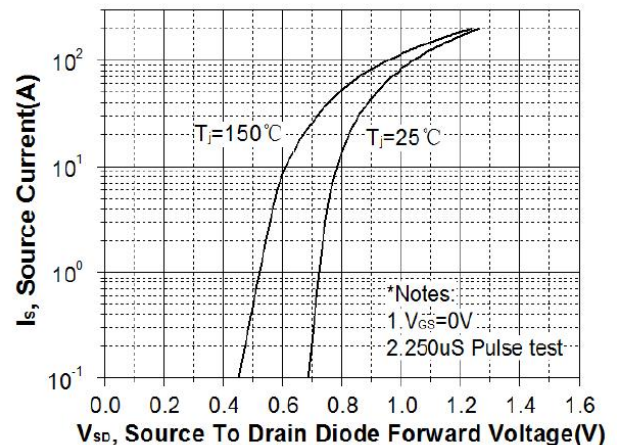


Fig. 4. On-state current vs. diode forward voltage

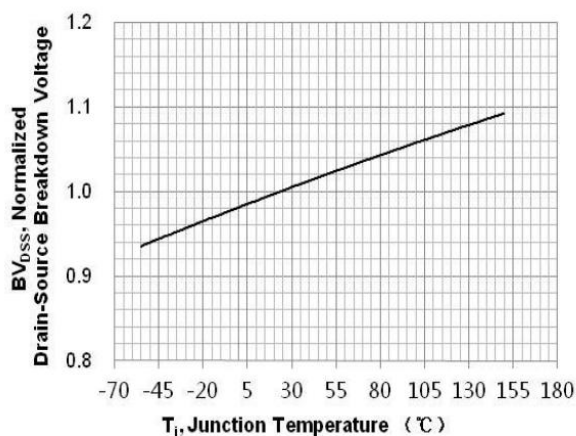


Fig. 5. Breakdown voltage variation vs. junction temperature

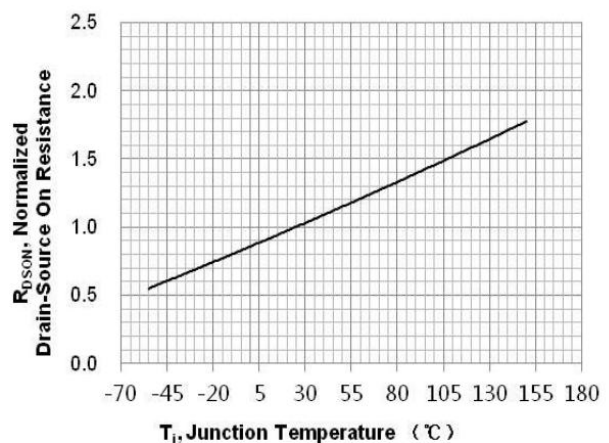


Fig. 6. On-resistance variation vs. junction temperature

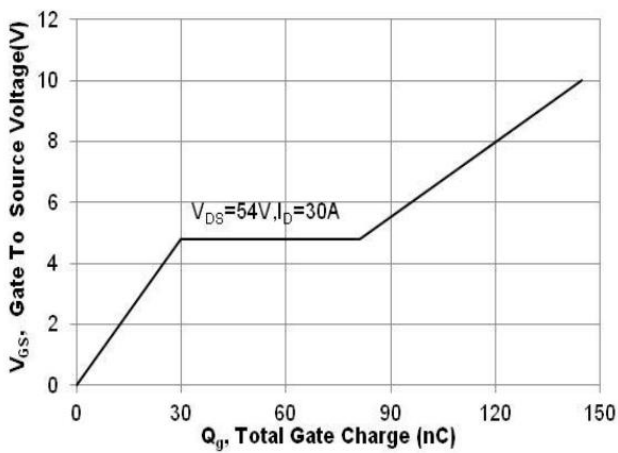


Fig. 7. Gate charge characteristics

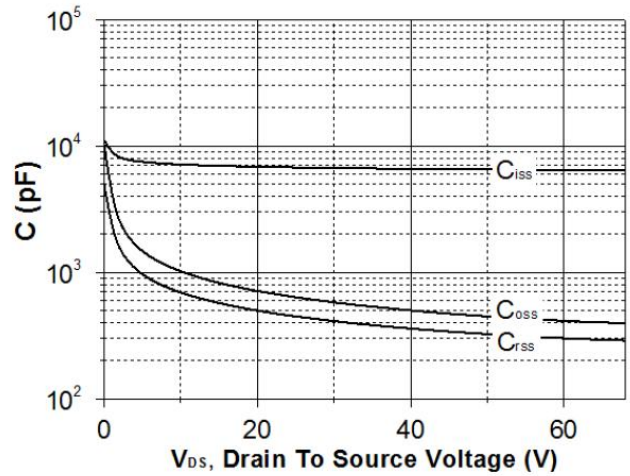


Fig. 8. Capacitance Characteristics

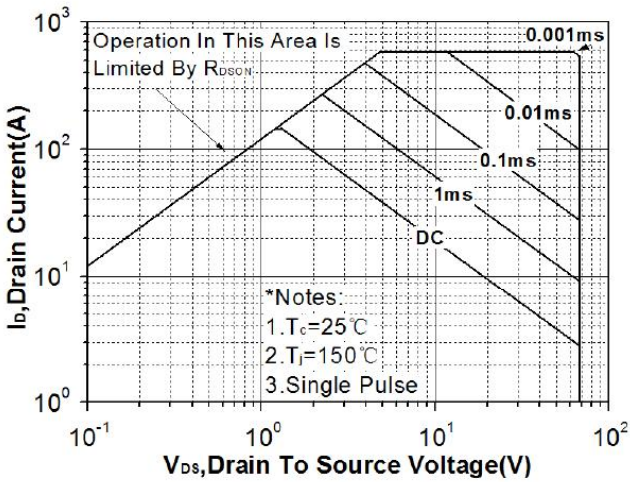


Fig. 9. Maximum safe operating area (TO220&TO263)

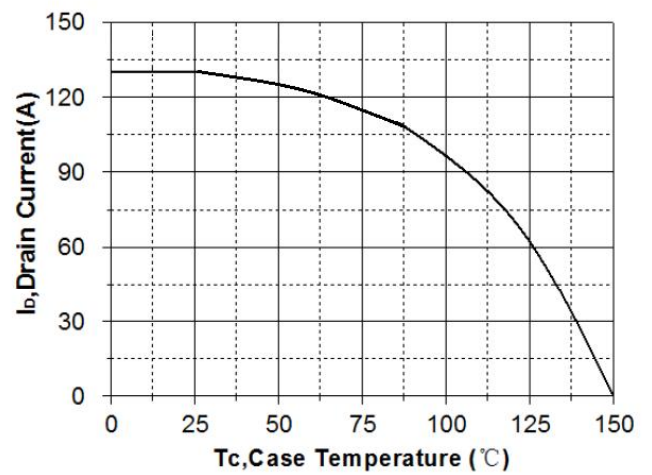


Fig. 10. Maximum drain current vs. case temperature (TO220&TO263)

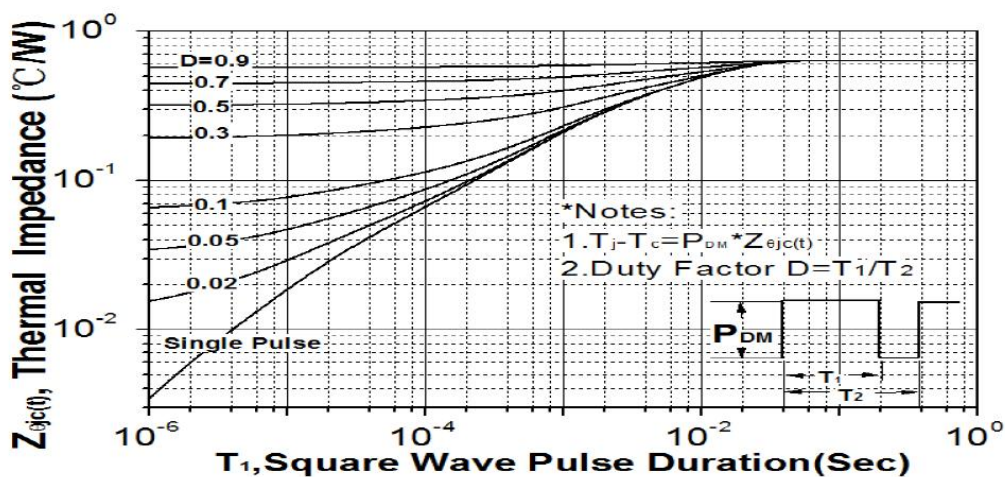
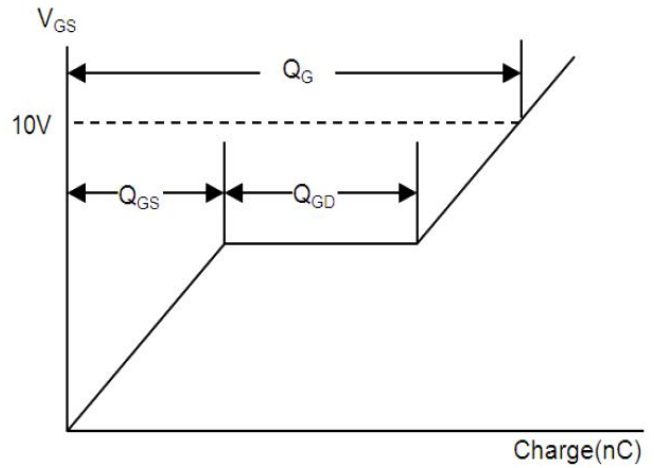
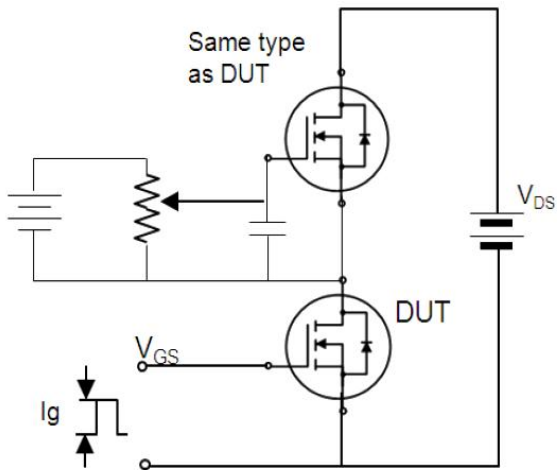


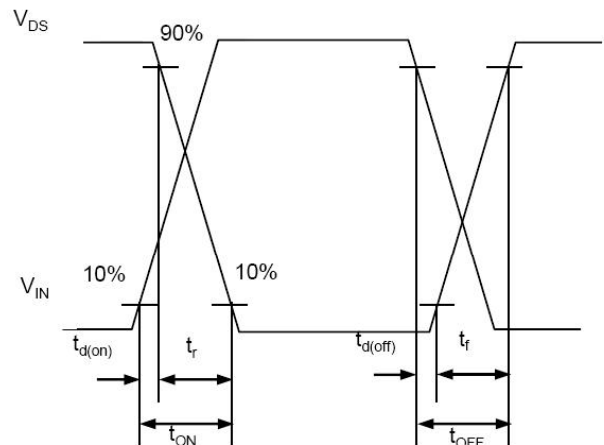
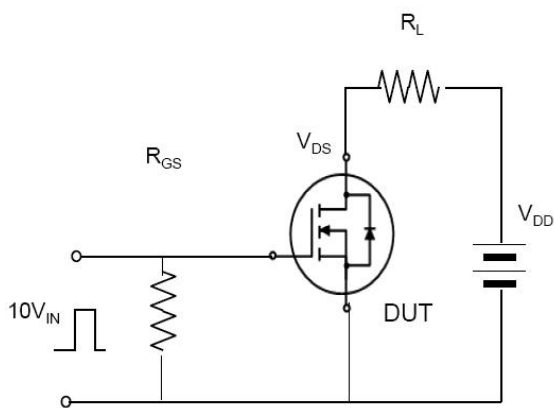
Fig. 11. Transient thermal response curve (TO220&TO263)



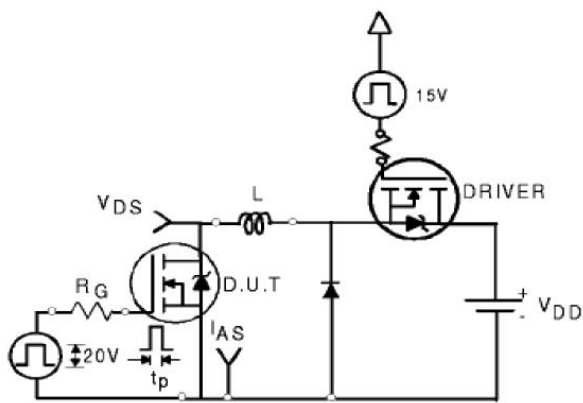
**10. Test Circuits and Waveforms**



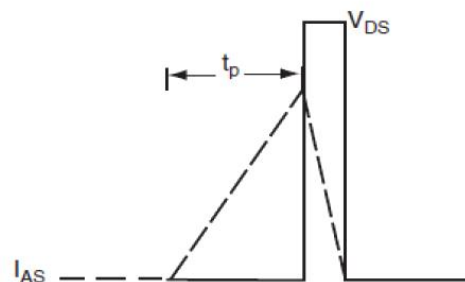
**Fig. 12. Gate charge test circuit & waveform**



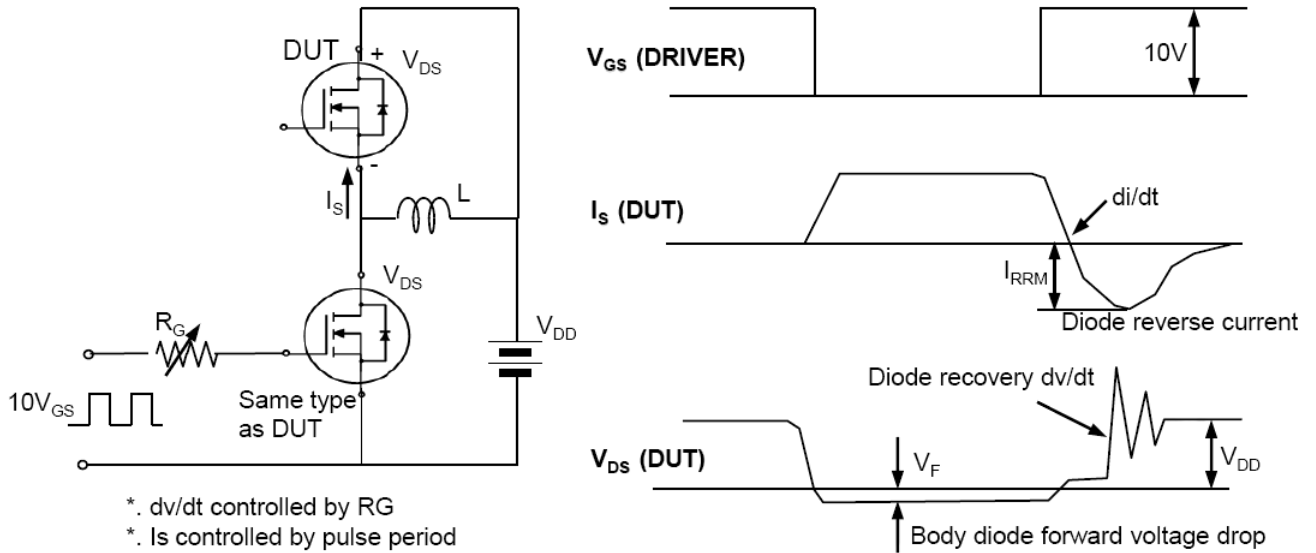
**Fig. 13. Switching time test circuit & waveform**



$$E_{AS} = \frac{1}{2} L I_{AS}^2$$



**Fig. 14. Unclamped Inductive switching test circuit & waveform**



**Fig. 15. Peak diode recovery  $dv/dt$  test circuit & waveform**